

Notice of References Cited	Application/Control No. 10/050,334		Applicant(s)/Patent Under Reexamination AGARWAL ET AL.	
	Examiner Yennhu B Huynh		Art Unit 2813	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	A	US-6,222,722	04-1999	Fukuzumi et al.	438/396
X	B	US-09/590795	06-2000	Agarwal et al.	438/496
X	C	US-6291289B2	09-2001	Rhodes et al.	438/239
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

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